

## FAN-OUT SEMICONDUCTOR CHIP ASSEMBLY

### Cross Reference To Related Applications

[0001] The present application is a continuation of United States Patent Application 08/935,962 filed September 23, 1997, which is a divisional of United States Patent Application 08/653,016, filed May 24, 1996, now United States Patent 5,688,710, which in turn is a continuation-in-part of United States Patent Application 08/440,665, filed May 15, 1995, now United States Patent 5,801,441, which in turn is a divisional of United States Patent Application 08/271,768, filed July 7, 1994, now United States Patent 5,518,964.

### Field of the Invention

[0002] The present invention relates to semiconductor chip assemblies and to methods and components useful in making such assemblies.

### Background Of The Invention

[0003] Complex microelectronic devices such as modern semiconductor chips require numerous connections to other electronic components. For example, a complex microprocessor chip may require many hundreds of connections to external devices.

[0004] Semiconductor chips commonly have been connected to electrical traces on mounting substrates by one of three methods: wire bonding, tape automated bonding, and flip-chip bonding. In wire bonding, the semiconductor chip is positioned on a substrate with a bottom or back surface of the chip abutting the substrate and with the contact-bearing front or top surface of the chip facing upwardly, away from the substrate. Individual gold or aluminum wires are connected between the contacts on the semiconductor chip and current conducting pads on the substrate. In tape automated bonding a flexible dielectric tape with a prefabricated array of leads

thereon is positioned over the semiconductor chip and substrate, and the individual leads are bonded to the contacts on the chip and to the current conducting pads on the substrate. In both wire bonding and conventional tape automated bonding, the current conducting pads on the substrate are arranged outside of the area covered by the semiconductor chip, so that the wires or leads fan out from the chip to the surrounding current conducting pads. The area covered by the subassembly as a whole is considerably larger than the area covered by the chip. This makes the entire assembly substantially larger than it otherwise would be. Because the speed with which a microelectronic assembly can operate is inversely related to its size, this presents a serious drawback. Moreover, the wire bonding and tape automated bonding approaches are generally most workable with semiconductor chips having contacts disposed in rows extending along the periphery of the chip. They generally do not lend themselves to use with chips having contacts disposed in a so-called area array, i.e., a grid-like pattern covering all or a substantial portion of the chip front surface.

[0005] In the flip-chip mounting technique, the contact bearing surface of the semiconductor chip faces towards the substrate. Each contact on the semiconductor chip is joined by a solder bond to the corresponding current carrying pad on the substrate, as by positioning solder balls on the substrate or contacts of the semiconductor chip, juxtaposing the chip with the substrate in the front-face-down orientation and momentarily melting or reflowing the solder. The flip-chip technique yields a compact assembly, which occupies an area of the substrate no larger than the area of the chip itself. However, flip-chip assemblies suffer from significant problems with thermal stress. The solder bonds between the contacts on the semiconductor chip and the current carrying pads on the substrate are substantially rigid. Changes in the size of the chip and of the substrate due to thermal expansion and contraction in service create substantial stresses in these







horizontally towards its own terminal end and vertically away from the terminal end. The net effect is to deform the leads towards formed positions in which the leads extend generally vertically downwardly, away from the first element. These methods may also include the step of injecting a flowable, desirably compliant dielectric material around the leads after the lead-forming step and then curing the flowable material so as to form a dielectric support layer around the leads.

[0010] In particularly preferred methods according to the '964 Patent application, one element is a flexible, dielectric top sheet having terminal structures thereon, and the other element includes one or more semiconductor chips. The resulting assembly thus includes the dielectric top sheet with the terminal structures connected to the associated contacts of the semiconductor chip or chips by the vertically-extending, curved flexible leads, the dielectric top sheet being spaced apart from the semiconductor chip or chips by the dielectric support layer. The terminal structures can be connected to a substrate such as a circuit panel to thereby provide electrical current communication to the contacts on the semiconductor chip or chips. Each terminal structure on the dielectric top sheet is movable with respect to the contacts in the semiconductor chip in horizontal directions parallel to the chip, as well as in vertical directions towards and away from the chip, to take up differences in thermal expansion between the chip and substrate and to facilitate testing and assembly.

[0011] The step of attaching the tip ends of the leads to the second element desirably includes the step of bonding the tip ends of the leads to the contacts on the semiconductor chip or chips while the leads are in their initial, undeformed positions. For example, a dielectric sheet having the leads disposed in generally horizontal orientation on its bottom surface may be juxtaposed with a chip or wafer so that the tip ends of the leads are engaged with the contacts of the chip or wafer. Thus, all of the tip ends are bonded simultaneously to







of the dielectric element and subassembly. The preferred method further includes the step of injecting a curable liquid between the dielectric element and the subassembly and curing the liquid to form a compliant layer supporting the dielectric element above the subassembly. The liquid may be injected under pressure, and the pressure of the liquid may force the dielectric element and subassembly away from one another.

[0014] Most preferably, the step of providing the subassembly includes the step of providing at least one peripheral support element disposed alongside of the chip in a peripheral region of the package element, the peripheral support element defining a front face facing codirectionally with the front face of the chip. Most preferably, the front face of the package element is substantially coplanar with the front face of the chip. The dielectric element overlies the front face of the peripheral support element or elements. Where the central region of the dielectric element overlies the front face of the chip, the portions of the compliant layer formed between the front face of the chip and the central region of the sheet will have substantially the same thickness as those portions of the compliant layer disposed between the peripheral regions of the sheet and the peripheral support elements. This assures that those portions of the compliant layer underlying each terminal will have substantially uniform resilient properties, further facilitating testing of the assembly and connection of the assembly to a larger substrate such as a circuit panel or multichip module.

[0015] Most preferably, the package element includes a heat sink, such as a metallic plate or vessel, and the heat sink is bonded to a back surface of the chip prior to the step of moving the sheet relative to the subassembly. The package element, and particularly the peripheral support elements included in the package element, desirably include at least one electrical circuit element. Most preferably, the method further includes the step of connecting each such electrical







[0025] Figure 5 is a diagrammatic view on an enlarged scale similar to Fig. 3, but depicting the components at the stage of the process illustrated in Fig. 4.

[0026] Figure 6 is a diagrammatic sectional view depicting the subassembly produced in the method of Figs. 1-5.

[0027] Figure 7 is a diagrammatic plan view of components illustrated in Figs. 1-6, with portions removed for clarity of illustration.

[0028] Figure 8 is a diagrammatic plan view depicting a component used in a further process according to the invention.

[0029] Figure 9 is a diagrammatic sectional view taken in Fig. 8, but showing the component in conjunction with a semiconductor chip.

[0030] Figure 10 is a sectional view depicting the completed assembly made by the process according to Figs. 8-9.

[0031] Figure 11 is a view similar to Fig. 10 but depicting a further embodiment of the invention.

[0032] Figure 12 is a diagrammatic plan view depicting components used in a process according to a further embodiment of the invention.

[0033] Figure 13 is a sectional view taken along lines 13-13 in Fig. 12, the components of Fig. 12 in conjunction with further components used in the process. Figure 14 is a sectional view similar to Fig. 13 but depicting the components during a later stage of the process.

[0034] Figure 15 is a diagrammatic sectional view depicting yet another embodiment of the invention.

#### Detailed Description of the Preferred Embodiments

[0035] A process in accordance with one embodiment of the present invention utilizes a semiconductor chip 20 having a front surface 22 with contacts 24 thereon and having an oppositely facing rear surface 24. The particular chip 20 illustrated in Fig. 1 has the contacts 24 disposed in an "area array", i.e., an array covering substantially the entire

front surface of the chip, with the contacts being uniformly spaced within the array. However, other types of chips may be used as, for example, chips having contacts disposed in rows adjacent the peripheral edges of the chip. Chip 20 is assembled with a composite package element 30 including a heat sink 26 and capacitors 32. Heat sink 26 is in the form of an open shell having a base wall 34, an edge wall 36 projecting from the base wall around the periphery thereof and a flange at the extremity of the base wall defining a generally planar flange surface 28 remote from the base wall. The auxiliary circuit elements or capacitors 32 are formed as generally rectilinear blocks each having a front surface 38 with terminals 40 thereon and a rear surface 42 facing oppositely from the front surface. As best seen in Figs. 1, 2, and 7 circuit elements or capacitors 32 are disposed in a ring-like array adjacent the flange 28 and peripheral wall 36 of the heat sink. The front surfaces 38 of the capacitors or auxiliary circuit elements 32 are substantially coplanar with another and substantially with the flange surface 28 of the heat sink. The rear surfaces 42 of the circuits element 38 are bonded to the base wall 34 of the heat sink by a thermally conductive adhesive layer 44. Adhesive layer 44 may include any of the well-known thermally conductive adhesive compositions, such as an epoxy loaded with metallic particles.

[0036] Semiconductor chip 20 is disposed in the center of the ringlike array of circuit elements. The rear face 24 of the chip is bonded to the base wall 34 of the heat sink by a further layer of thermally conductive epoxy 44. The thickness or front to rear face dimension of chip 20 is the same as the corresponding dimensions of the auxiliary circuit elements or capacitor 38. The front face 22 of chip 20 is substantially coplanar with the front faces 38 of the auxiliary circuit elements or capacitor 32 and with the flange 28 of the heat sink. As used in this disclosure, the term "substantially coplanar" means that the surfaces are coplanar with one another to within about 125 microns or less. Although gaps

are shown between adjacent edges of the chip and auxiliary circuit elements 32, and between the various auxiliary circuit elements, it should be appreciated that the size of these gaps is exaggerated in the drawings for clarity of illustration. Preferably, the various components are separated from one another by horizontal distances of no more than about 0.5 mm. The auxiliary circuit elements and the chip are positioned precisely on the heat sink relative to one another, so that the terminals 40 of the auxiliary circuit elements lie in predetermined spatial relationship to the terminals 24 of the chip. As discussed below, the contacts 40 of the auxiliary circuit elements 32 are connected to leads in a common process with the contacts 24 of the chip, and the predetermined spatial relationship should be maintained to facilitate simultaneous connection of all of these contacts. The degree of accuracy with which the auxiliary circuit elements must be positioned relative to the chip is inversely related to the size of the contacts on the auxiliary circuit elements. Typically, the auxiliary circuit elements require fewer contacts than the chip itself and possess substantial front-surface area over which the contacts can be distributed. Thus, the contacts 40 on the auxiliary circuit elements may be substantially larger than the contacts 24 on the chip.

[0037] In the next stage of the process, the subassembly 50, shown in Fig. 2, including the auxiliary circuit elements, heat sink and chip is juxtaposed with a flexible, sheetlike dielectric element 52. The dielectric element 52 includes a dielectric body incorporating one or more layers of a flexible, but substantially inextensible dielectric material. These flexible layers may include thin sheets of polyimide, typically having an aggregate thickness of about 25 microns (.001 inch). Dielectric sheet 52 has a top surface 54 and a bottom surface 56. The sheet has a central region 57 overlying the chip, and a peripheral region 59 surrounding the central region. Electrically conductive metallic terminals 58 are distributed substantially uniformly over the entire area

of the top surface, including the central region and the peripheral region. As best seen in Fig. 3, the terminals 58 are formed as the upper extremities of metal-lined vias extending vertically within the dielectric element 52. The dielectric element further has first leads 60 extending along the bottom surface 56 in central region 57, and second leads 64 extending along the bottom surface 56 in a peripheral region 59. The dielectric sheet also has conductors 66 extending horizontally along the sheet. The conductors may extend on the top surface 54, on the bottom surface 56, or between the surfaces.

[0038] Each first lead 62 has a terminal end 68 (Fig. 3) permanently attached to the bottom of sheet 52 and a tip end 70 remote from such terminal end releasably attached to the bottom surface of the sheet. The permanent attachment may be constituted by a metallurgical bond between the terminal ends 68 and the vias 60 extending through the sheet or into the sheet from the bottom surface 56. The structure of these leads may be the same as described in the aforementioned '964 Patent. Merely by way of example, leads 62 may have curved sections extending between the tip ends and the terminal ends. The second leads 64, in peripheral region 59, have a generally similar configuration. Thus, each such second lead has a terminal end 72 permanently attached to the sheet and a tip end 74 releasably attached to the sheet bottom surface 56. Each of the tip ends 70 and 74 may have bonding material thereon. The bonding materials may be eutectic bonding alloys or other materials which can be captivated upon exposure to elevated temperature and which form a solid bond with the leads and contacts. For example, where the lead tip ends and the chip contacts include gold, the bonding material may include tin silicon or alloys thereof with gold. Many other bonding materials are described in the '964 Patent, and can be used in the present invention.

[0039] The terminals 58, first leads 62, and second leads 64 are electrically interconnected with one another. Some or



all of the first leads 62 are electrically connected to terminals 58 by vias 60 and by conductors 66 on the sheet. Some of the terminals, such as terminal 58a disposed in the central region of the sheet may be directly connected to the terminal ends of first leads, such as lead 62a, whereas other terminals 58b disposed in the peripheral region of the sheet are connected to the terminal ends of the associated leads by conductors 66 and one or more of the vias 60. The terminal ends 72 of the second leads may be connected to certain conductors 66. Some of the conductors thus interconnect the terminal end of a first lead 62 with the terminal end of a second lead 64. Others of the terminal ends of the second leads 64 can be connected to other terminals 58.

[0040] As best seen in Figs. 2 and 3, sheet 58 is juxtaposed with subassembly 50 by holding the sheet on an upper tool or platen 80, holding the subassembly 50 in a lower tool or platen 82 and aligning the two tools so that the tip ends 70 of first leads 62 are aligned with the contacts 24 of the chip and so that the tip ends 74 of the second leads 64 are aligned with the contacts 40 of the auxiliary circuit elements or capacitors 32. The sheet and subassembly may be held in a position on the tools during this process by any convenient mechanical method as, for example, by vacuum ports 86 in the tools, or by temporarily bonding the sheet and/or the heat sink to their respective tools. Preferably, the upper tool 80 is transparent, or includes a transparent window, so that the dielectric sheet can be aligned with the chip under manual, visual control or by automated vision systems. The techniques used for aligning the sheet with the subassembly may be similar to those used for aligning elements as described in the '964 Patent. Provided that the relative positions of the auxiliary circuit elements or capacitors 32 and chip 20 are controlled as discussed above during formation of the subassembly, the tip ends or the leads can be aligned with the associated contacts on the chip and auxiliary circuit elements simultaneously. Where the contacts 40 on the

auxiliary circuit elements are larger than the contacts 24 on the chip, the alignment can be controlled so as to precisely match the positions of the first lead tip ends 70 with the chip contacts 24. Even if the auxiliary circuit elements are slightly out of nominal position relative to the chip, the tip ends 74 of the second leads 64 will still be aligned with the relatively large contacts on these elements.

[0041] Tools 80 and 82 are forced together so as to force all of the tip ends of the leads into engagement with the associated contacts, and heat is applied so as to activate the bonding material on the tip ends of the leads, thereby fusing the tip ends of the lead to the contacts 24 and 40 on the chip and on the auxiliary circuit element. The space between the subassembly and sheet is substantially evacuated. Tools 80 and 82 may be provided with suitable seals around their peripheries (not shown) and suitable ports for connecting the space between the sheet and subassembly to a vacuum source to accomplish such evacuation. In the next stage of the process (Figs. 4 and 5), sheet 52 and subassembly 50 are moved vertically away from one another by moving tool 80 vertically away from tool 82. During this stage of the process, the subassembly and sheet are held in engagement with tools 80 and 82, as by vacuum applied through ports 86 or by other suitable means. During the moving step, a curable liquid 90 adapted to form a compliant material upon curing such as a liquid precursor adapted to form a silicone gel upon curing is injected under pressure into the space between the sheet and the subassembly. The pressure of liquid 90 also tends to force sheet 52 upwardly against tool 80 and thereby tends to force the terminals 58 into engagement with the planar surface 81 of the tool. Stated another way, the contacts 58 are forcibly moved into coplanar alignment with one another by the fluid pressure.

[0042] As the sheet moves upwardly, away from the subassembly 50, the tip ends 70 and 74 of the leads remain in place on the chip contacts 24 and circuit element contacts 40,



[0044] After curing, the edges of sheet 52 and any excess compliant material can be trimmed away from the assembly. The resulting assembly can be tested by engaging all of the terminals 50 with terminals on a test fixture (not shown). The compliant layer facilitates such engagement. The assembly can be assembled to a substrate 96 (Fig. 6) such as a circuit panel having contact pads 98 thereon as by interposing solder masses 100 between terminals 58 and the contact pads and sattering the assembly in place. This operation may be performed using standard surface mount soldering techniques.

[0045] As schematically depicted in Fig. 7, some of the terminals 58 (schematically denoted by the symbol "x") are interconnected by the conductors 66 with the terminals 40 of auxiliary circuit elements or capacitors 32, and the terminals 40 of the auxiliary circuit elements are also connected to the contacts 24 of the chip by other conductors 66 on the sheet. Thus, the auxiliary circuit elements are connected in circuit with the chip. As is well-known in the art, such auxiliary circuit elements typically are connected into the circuit at the power and ground connections of a semiconductor chip. Thus, the particular terminals 58, connected to the contact 40 of the auxiliary circuit element are connected to the power and ground connections of substrate 96 and to the power and ground connections of the chip. The other terminals 58 typically are employed for signal connections to the chip.

[0046] Numerous variations and combinations of the features described above can be utilized. In one such variation, chip 22 and each of the auxiliary circuit elements 38 can be attached separately to sheet 52. The contacts on the chip 20 are aligned with the tip ends of the first leads 62 and the chip is engaged with the sheet while applying heat and pressure. The contacts of each auxiliary circuit element 32 are aligned with the tip ends of second leads 64 and bonded thereto in a separate operation. A process for engaging plural elements separately with a dielectric sheet is described in detail in copending, commonly assigned U.S.

Patent Application No. 08/532,528, filed September 25, 1995, the disclosure of which is hereby incorporated by reference herein. After all of the elements have been attached to the sheet and the contacts of the respective elements have been bonded to the tip ends of the respective leads, the back surfaces of the various elements may be bonded to the heat sink 26. Stated another way, the subassembly of the chip with the heat sink and auxiliary circuit elements can be formed in place on the dielectric sheet after the chip and auxiliary circuit elements have been attached to the tip ends of the leads. In a further variant, the auxiliary circuit elements may be omitted and hence the subassembly of the chip and the package element may consist only of the chip and heat sink. In yet another variation, all of the auxiliary circuit elements or capacitors 32 may be formed as a unitary ring-like element. Alternatively or additionally, the package element may include one or more inert blocks or rings having no electrical function, but which serve solely to surround the chip and support the compliant layer and dielectric layer in the finished package. According to yet another variant, the auxiliary electrical circuit elements may include one or more additional chips which are connected in circuit with the principal chip by the conductors on the dielectric element. In this variant, the assembly constitutes a multichip module. In yet another variant, a plurality of assemblies may be formed simultaneously by using a plurality of chips and a plurality of package elements, and a dielectric element large enough to cover all of the chips and package elements. After connecting each chip to the overlying region of the large dielectric element by leads as discussed above, the dielectric element is moved relative to the chips and package elements, and the liquid material is injected to form a large compliant layer. The dielectric element and compliant layer are severed to provide individual modules, each including one chip or a few chips and the associated package element. In a further variant of this approach, the package element may also be a

large element, such as a continuous plate. The plate may be cut during the severing step to provide individual package elements, each associated with one module.

[0047] In yet another variant, the dielectric sheet 152 (Fig. 8) has elongated apertures merging with one another to form a continuous slot 153 surrounding an island portion 155 within the central region 157 of the sheet, and subdividing portion 155 from the remainder of the sheet. The first leads 162 are disposed in rows extending across slot 153. The leads within each row extend generally parallel to one another. One end of each lead is disposed on island portion 155, whereas the opposite end of each lead 162 is disposed on the main portion of the sheet. Each lead includes a frangible region 163 aligned with or adjacent to slot 153. The lead structures used in this arrangement may be substantially as shown and described in International Patent Publication WO 94/03036, the disclosure of which is hereby incorporated by reference herein. The sheet bears terminals 158 on its top surface, in the peripheral region of the sheet. These terminals are connected by conductors 160 to leads 162. A chip 120 has contacts 124 disposed in rows on the front face of the chip, adjacent to the edges of the chip.

[0048] In an assembly process, the chip is aligned with the sheet so that each row of contacts is aligned with a portion of slot 153 and with one row of leads 162. Each lead is bonded to a contact on the chip by engaging the lead with a bonding tool and forcing the lead downwardly, into slot 153, in the manner taught in the '036 publication. The downward movement breaks the frangible section of each lead and detaches the end of the lead from the island region 155 of the sheet. When all of the leads have been connected to the chip in this manner, the island region of the sheet is disconnected from the remainder of the sheet, and can be lifted away from the remainder of the sheet, leaving a hole in the central region of the sheet. A package element such as a heat sink 126 is attached to the back surface of the chip, thus forming









